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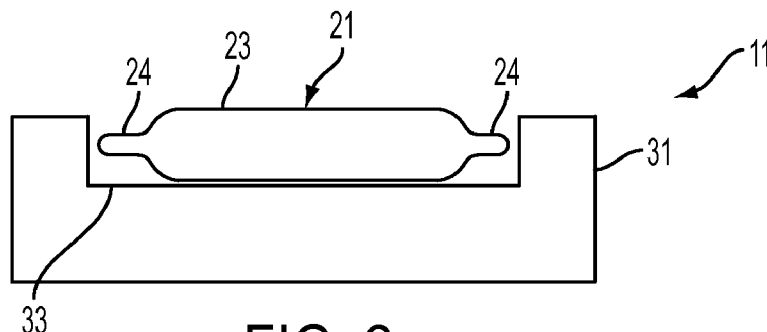


FIG. 2

(57) Abstract: A sample holding device and related method designed to facilitate inexpensive and reliable testing of materials or specimens with beam diffraction and scattering techniques. The device features a sample receptacle that is made out of a polymer, cellulose, polymeric material, or cellulosic material. The flexible nature and low melting point of the sample receptacle allows for reliable sealing against the vacuum or gaseous environment used for beam diffraction or scattering analysis. The sample holding device can be considered disposable because of its low cost, eliminating the need for complex or unreliable cleaning procedures.

Device and Related Method for Solution Scattering and Diffraction Sample Holders**CROSS-REFERENCE TO RELATED APPLICATIONS**

The present application claims benefit of priority under 35 U.S.C. §119(e) from U.S. Provisional Application Serial No. 61/892,892, filed October 18, 2013, entitled “Device and Related Method for X-Ray Scattering Sample Holders;” the disclosure of which is hereby incorporated by reference herein in its entirety.

FIELD OF THE INVENTION

The present invention relates generally to the field of beam scattering and diffraction. More specifically, the invention relates to the subfields of x-ray crystallography and x-ray solution scattering and diffraction, and the equipment used therein.

STATEMENT OF GOVERNMENT INTEREST

This invention was made with government support under Grant No. 1U54GM094611 awarded by the National Institutes of Health. The government has certain rights in the invention.

BACKGROUND

Beam scattering and diffraction are useful analytical tools used by researchers to determine the size, structure, and properties of molecules or other very small structures. Beam scattering and diffraction involve the use of an energy source that produces a beam, usually of x-rays, though other wavelengths or particle beams may also be used. The beam is passed through a sample, which is entrained in a receptacle. The beam is diffracted in the sample, and then continues on to a detector which reads the scattered or diffracted beam. Researchers are then able to determine properties of the material sample and reconstruct aspects of its structure, such as molecular weight, size, and composition. When the sample consists of spatially uncorrelated or disordered particles, such as atoms or molecules, the interaction of light or a beam with said sample is called scattering. When the sample consists

of spatially correlated or ordered particles, such as atoms or molecules, the interaction of light or a beam with said sample is called diffraction.

Researchers are currently forced to use quartz or capillary tubes that entrain the sample to be tested, particularly in the case of solution scattering analysis. However, these types of tubes have a number of drawbacks, which make solution scattering analysis expensive, difficult, or impractical. Glass or quartz capillaries, often part of other complex sample containment assemblies, are costly, easily broken, and difficult to seal. Notably, the glass or quartz capillaries cannot be self sealed because the heat required to melt the capillary tube is so high that it would damage or degrade most sample materials, particularly liquids. Furthermore, glass or quartz capillaries may prevent the testing of certain difficult to procure samples, because sample recovery may be complex or impossible with existing sample receptacles. Also, because of their significant cost, glass or quartz capillaries are not disposable, requiring unreliable and time consuming cleaning steps which may lead to the contamination of subsequent samples from incomplete removal of previous samples or the cleaning fluids themselves.

There is a need in the art for a sample holding device which is inexpensive, robust, easy to manufacture, reduces contamination, and which allows for recovery of the working sample.

OVERVIEW

Beam scattering and diffraction techniques are very useful to researchers attempting to analyze the molecular structure of a specimen. Oftentimes these techniques are not used because of the difficulty of testing specimens, particularly in liquid phase, with existing testing equipment. However, the use of an embodiment of the present invention polymer, polymeric, cellulose, or cellulosic sample receptacle shall improve the beam scattering and diffraction testing processes and make it more viable across a wider range of potential applications.

An aspect of an embodiment of the present invention device and its associated method provides, among other things, the user with an inexpensive, easy to use, and effective sample holding device. In one aspect, an embodiment of the device utilizes, for example, a polymer, polymeric material, cellulose, or cellulosic material for a sample receptacle. A number of advantages result from this change in material. The polymer, cellulose, polymeric, or

cellulosic sample receptacles are much less expensive and do not easily shatter like quartz or glass tubes. Furthermore, polymer, cellulose, polymeric, or cellulosic sample receptacles can be easily mass-produced so that researchers may dispose of the sample receptacle after a single use. This greatly simplifies the beam scattering and diffraction testing processes because no cleaning between specimens is required, eliminating a time consuming step and the potential for contamination.

Using a polymer, cellulose, polymeric, or cellulosic sample receptacle also offers a number of advantages for sealing specimens in the sample receptacle. The more flexible and pliable nature of the sample receptacle of an embodiment of the present invention allows for, among other things, sealing that is more effective and reliable than methods used with glass or quartz tubes, for example. Additionally, another advantage of a polymer, cellulose, polymeric, or cellulosic material of an embodiment of the present invention is, but not limited thereto, that it has a melt temperature low enough to allow for heat sealing of the sample receptacle at temperatures that are not likely to damage or degrade specimens. This dramatically reduces the possibility of specimen loss, particularly when the beam scattering or diffraction test is carried out in a vacuum that could pull the specimen from the sample receptacle. It is also advantageous that the sample receptacle of an embodiment of the present invention may be sealed independently from any device or apparatus that may be used to hold the sample receptacle.

Another aspect of an embodiment of the present invention sample holding device is that recovery of the specimen is straightforward and reliable with a polymer, polymeric, cellulose, or cellulosic sample receptacle. Since polymers, polymeric materials, cellulose, or cellulosic materials are relatively soft and pliable, a specimen, especially if it is in liquid phase, may be recovered by piercing the sample receptacle material and drawing the specimen back out. This could be done with a syringe (or any applicable device) or by cutting the sample receptacle. Since the material is flexible and will not shatter, there is no chance of contamination due to small particles of broken glass or quartz remaining in the specimen. It is also possible to easily mold in or attach access apertures to the sample receptacle to facilitate deposit and removal of specimens (or other materials as desired or required) from the sample receptacle.

An aspect of an embodiment of the present invention provides, among other things, a device for use in solution scattering or diffraction. The device may comprise at least one sample receptacle comprising, at least in part, a polymer material, polymeric material,

cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle configured to accommodate a sample; a retainer, the retainer configured to removably hold the at least one sample receptacle and allow for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and wherein the at least one sample receptacle is configured to be sealable for containing the sample, wherein sealing is independent of the retainer.

An aspect of an embodiment of the present invention provides, among other things, a method for solution scattering or diffraction. The method may method comprise: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle accommodating a sample; holding the at least one sample receptacle and allowing for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and sealing the at least one sample receptacle for containing the sample.

An aspect of an embodiment of the present invention provides, among other things, a method for solution scattering or diffraction. The method may comprise: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle configured to accommodate a sample; providing a retainer configured for holding the at least one sample receptacle and allowing for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and the sample receptacle configured to allow the sample to be sealed in the at least one sample receptacle for containing the sample.

An aspect of an embodiment of the present invention provides, among other things, a method for solution scattering or diffraction. The method may comprise: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle configured to accommodate a sample; wherein the at least one sample receptacle is configured to allow the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and the sample receptacle configured to allow the sample to be sealed in the at least one sample receptacle for containing the sample.

An aspect of an embodiment of the present invention provides, among other things, a sample holding device and related method designed to facilitate inexpensive and reliable

testing of materials or specimens with beam diffraction and scattering techniques. An aspect of an embodiment of the present invention device features a sample receptacle that may be made out of a polymer, cellulose, polymeric material, or cellulosic material. The flexible nature and low melting point of the sample receptacle allows for reliable sealing against the vacuum or gaseous environment used for beam diffraction or scattering analysis. The sample holding device can be considered disposable because, among other things, of its low cost, thereby eliminating the need for complex or unreliable cleaning procedures. Using a polymer, polymeric material, cellulose, or a cellulosic material (or other like material selected as desired or required) prevents breakage of sample receptacles and allows for recovery of a specimen after beam scattering or diffraction testing is complete. The specific polymer, polymeric material, cellulose, or cellulosic material selected (or other material selection as desired or required) can be tailored to different wavelengths or beam types, blocking certain wavelengths while allowing others to pass through.

These and other objects, along with advantages and features of various aspects of embodiments of the invention disclosed herein, will be made more apparent from the description, drawings and claims that follow.

BRIEF DESCRIPTION OF THE DRAWINGS

The accompanying drawings, which are incorporated into and form a part of the instant specification, illustrate several aspects and embodiments of the present invention and, together with the description herein, serve to explain the principles of the invention. The drawings are provided only for the purpose of illustrating select embodiments of the invention and are not to be construed as limiting the invention.

Figure 1 provides a schematic illustration of an embodiment of the present invention being used in conjunction with an x-ray scattering system.

Figure 2 provides a schematic illustration of an embodiment of the present invention sample holding device.

Figure 3 provides a schematic illustration of an embodiment of the present invention sample holding device incorporating an adapter or insert.

Figure 4 provides a schematic illustration of an embodiment of the present invention sample holding device incorporating multiple adapters or inserts.

Figure 5 provides a schematic illustration of an embodiment of the present invention sample holding device with multiple compartments.

Figure 6 provides a schematic illustration of an embodiment of the present invention sample holding device with a retainer at one end.

Figure 7 provides a schematic illustration of an embodiment of the present invention sample holding device with multiple retainers.

Figure 8 provides a schematic illustration of an embodiment of the present invention sample holding device with a centrally located retainer.

Figure 9 provides a schematic illustration of an embodiment of the present invention sample holding device with a full length retainer at one end.

Figure 10 provides a schematic illustration of multiple exemplary sample holding devices in a linear rack.

Figure 11 provides a schematic illustration of multiple exemplary sample holding devices in a circular or rounded rack.

Figure 12 provides a schematic illustration of multiple exemplary sample holding devices in a flexible or articulating rack.

Figure 13 provides a schematic illustration of exemplary embodiments of the present invention sample holding device sample receptacles.

Figure 14 provides a schematic illustration of an exemplary embodiment of the present invention sample holding device retainer.

Figure 15 provides a schematic illustration of an exemplary embodiment of the present invention sample holding device with a sample receptacle disposed therein.

Figure 16 provides a schematic illustration of an exemplary embodiment of the present invention sample holding device and exemplary constituent parts.

Figure 17 provides a schematic illustration of an exemplary embodiment of the present invention sample holding device in an exemplary moveable rack.

DETAILED DESCRIPTION OF EXEMPLARY EMBODIMENTS OF THE PRESENT INVENTION

Figure 1 provides a schematic depiction of an aspect of an embodiment of the present invention sample receptacle **21** and retainer **31** being used in conjunction with an x-ray scattering system **61**. An energy source **63** generates an x-ray beam **62**, which is aimed at the

sample receptacle **21**. The sample receptacle **21** is positioned between the energy source **63** and a detector **64** by a retainer **31**. The x-ray beam **62** passes through the sample receptacle **21** and the sample, which is held therein. After exiting the sample receptacle **21**, a scattered x-ray beam **66** is directed towards the detector **64** to be measured and analyzed. It should be appreciated that this schematic illustration shows a general arrangement of the sample receptacle **21** and retainer **31** being used in conjunction with the x-ray scattering system **61**. The sample receptacle **21** and retainer **31** may take on various different forms, as may the x-ray scattering system **61**. Furthermore, it should be appreciated that the sample receptacle **21** and retainer **31** may be used with numerous different types of systems which may incorporate x-rays, gamma rays, ultraviolet light, visible light, infrared light, or any other wavelength or frequency of the electromagnetic spectrum that may be desired or required by the user.

Figure 2 provides a schematic illustration of an embodiment of the present invention sample holding device **11**. The device **11** may be comprised of a sample receptacle **21** that is located on or within a retainer **31**. The sample receptacle **21** may be configured with a compartment **23** that is suited for retaining a sample to be tested. It should be appreciated that the sample receptacle **21** is manufactured from, or otherwise made from, at least in part, a polymer material, a polymeric material, a cellulose material, a cellulosic material, or any combination thereof. It should be appreciated that the sample receptacle **21** may be manufactured from other materials as desired or required to meet the operational and structural demands. For example, but not limited thereto, the sample receptacle **21** may be comprised of any material that provides for the flexible and pliable nature of the sample receptacle **21**. The sample receptacle **21** may have seals **24** which contain the sample (not shown) within the compartment **23** of the sample receptacle **21**. These seals **24**, of which there may be one, two, or more as desired, required or needed, may be achieved in any number of different ways so as to suit the needs of a particular application. For example, the seals **24** may comprise any number of different methods including heat seals, mechanical seals, such as clips, pins, clamps, or other mechanical sealing means, adhesion seals, such as glue, epoxy, or through other bonding agents, or chemical seals including chemicals that may melt or otherwise close the ends of the sample receptacle **21**. It may also be desirable to use liquids that may be applied to the ends of the sample receptacle that dry in place to form a plug or seal that will serve to contain a sample in the sample receptacle **21**. It should be appreciated that, because of the choice of a polymer, polymeric, cellulose, or cellulosic material for the sample receptacle **21**, heat sealing methods may be considered preferable in a

number of applications. Specifically, the sample receptacle **21**, made of the aforementioned materials, may have heat applied to the ends to melt the sample receptacle **21** to create seals **24**. This method of sealing may be preferable for a number of applications because it is inexpensive, secure, easy to achieve even on small sample receptacles, and should not require so much heat as to damage or degrade the sample entrained within the sample receptacle **21**. It should be appreciated that the sample receptacle may take on all shapes along the entire continual geometric spectrum of manipulation of x, y and z planes for containing a sample during any stage of its use, as well as being configured to be secured appropriately during any stage of use. For example, some exemplary shapes of the sample receptacle may include, but not limited thereto, spherical, cubical, cuboid, prismatic, pyramidal, tubular, or cylindrical, as well as any combinations thereof.

Still referring to **Figure 2**, the retainer **31** is depicted with a cavity **33**. This cavity, which may take on any number of shapes or forms including, but not limited to, a channel, aperture, depression, crease, opening, or slot is configured to removably hold at least one sample receptacle **21** and allow for the sample receptacle **21** to be in communication with an energy beam. The sample receptacle **21** may be held in place in the retainer **31** by any number of means including, but not limited to, mechanical attachments, friction fit retention, interference fit retention, magnetic retention, or adhesive retention. It should be appreciated that retention means such as clips, snap fittings, or hook and loop fasteners may be used to achieve retention of the sample receptacle **21** in the cavity **33** of retainer **31**.

Figure 3 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** incorporating an adapter or insert **34** or the like. Once again, the device **11** may be configured with a sample receptacle **21** which is comprised of a compartment **23** and seals **24** to contain the sample (not shown). The sample receptacle **21** may be held or placed within the cavity **33** of the retainer **31**. The sample receptacle **21** is in communication with an adapter or insert **34**, which is likewise in communication with the retainer **31**. The sample receptacle **21** may be held or retained by the adapter or insert **34** by any number of attachment or retention means, including, but not limited to, a friction fit, interference fit, snap fits, clips, magnets, hook and loop fasteners, adhesives, or any other attachment or retention means as desired, required, or needed by the particular application. Furthermore, an adapter or insert may include other attachment or retention means including wedges, clay, foam, wax, or any other secure attachment. The adapter or insert **34** is configured so as to facilitate the mating of the sample receptacle **21** and the retainer **31**. It

should be appreciated that multiple types or configurations of adapter or insert **34** may be used with a single retainer **31** to accommodate any number of different sample receptacle **21** configurations, or vice versa. In this particular schematic illustration, the adapter or insert **34** is shown positioned lengthwise with the sample receptacle **21**, however this is only an illustrative example, and the adapter or insert **34** may be oriented transversely, at the ends, along the sides, or in any other relation to the sample receptacle **21**. Furthermore, although not shown, it should be appreciated that the adapter or insert **34** may be configured to be used as a door, lid, latch, cross-member, or hatch to enclose the sample receptacle **21** within the cavity **33** of the retainer **31**.

Figure 4 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** incorporating multiple adapters or inserts **34**. Once again, the device **11** is shown having a sample receptacle **21** with a compartment **23** configured to hold a sample (not shown) and seals **24** configured to retain the sample in the compartment **23**. Multiple adapters or inserts **34** are shown located in communication with the seals **24** and the cavity **33** of the retainer **31**. Here, again, the adapters or retainers **34** may take on any number of attachment or retention means, including, but not limited to, a friction fit, interference fit, snap fits, clips, magnets, hook and loop fasteners, adhesives, or any other attachment or retention means as desired, required, or needed by the particular application. Furthermore, an adapter or insert may include other attachment or retention means including wedges, clay, foam, wax, or any other secure attachment. It should be appreciated that the adapters or inserts **34** may be disposed, located, or arranged in any relationship to either the sample receptacle **21** or the retainer **31**. For example, the adapters or inserts **34** may be arranged at the ends of the sample receptacle **21**, along the sides, laterally, longitudinally, transversely, parallel to the sample receptacle **21**, or in any other relation as desired or required for any particular application. The adapters or inserts **34** are configured so as to facilitate the mating of the sample receptacle **21** and the retainer **31**. It should be appreciated that multiple types or configurations of adapters or inserts **34** may be used with a single retainer **31** to accommodate any number of different sample receptacle **21** configurations, or vice versa. For example, although not shown, the multiple adapters or inserts **34** may be located in communication with the sample receptacle without being in communication with the seals **24**. Alternatively, although not shown, the multiple adapters or inserts **34** may be located in communication with the sample receptacle while being in communication with both the seals **24** as well as other portions of the sample receptacle **21**.

Figure 5 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** with a sample receptacle **21** which is comprised of multiple compartments **23** for holding multiple samples (not shown) which are separated and bound by multiple seals **24**. The sample receptacle **21** is located within the cavity **33** of the retainer **31**. It should be appreciated that the sample receptacle **21** may have as many compartments **23** as necessary or practical for any particular application. Furthermore, the compartments **23** may be arranged in any way as desired or required by the user, and is not limited to compartments that are linearly disposed. The sample receptacle **21** may be configured to allow for compartments **23** to be arranged in a closed shape, such as a circle, square, rectangular, polygonal, elliptical, or other shape as necessary. It should be appreciated that any of the aforementioned methods for creating seals **24** and attaching or retaining the sample receptacle **21**, with or without an adapter or insert, would be viable for a sample receptacle **21** with multiple compartments **23**. It should be appreciated, in an alternative embodiment, that seals are not provided between compartments so as to allow flow or transfer of samples or other materials between the compartments as desired or required. Accordingly, for example, a type of transfer path or transfer area would be provided between the compartments to accommodate the movement or flow of the sample or other material.

Figure 6 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** with a retainer **31** located at one end of the sample receptacle **21**. The sample receptacle **21**, including the compartment **23** and seals **24** for containing a sample (not shown), is located and retained by a retainer **31** at one end of the sample receptacle **21**. It should be appreciated that the retainer **31** may be located at either end of the sample receptacle **21**, and that the retainer **31** may be configured or arranged so as to hold the sample receptacle **21** vertically, horizontally, or at any angle as desired, required, or needed.

Figure 7 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** with multiple retainers **31**. The sample receptacle **21**, including compartment **23** and seals **24** for containing a sample (not shown), is located and retained by multiple retainers **31** at either end of the sample receptacle **21**. It should be appreciated that the retainers **31** may be located at any location on the sample receptacle **21**, and that the retainers **31** may be configured or arranged so as to hold the

sample receptacle **21** vertically, horizontally, or at any angle as desired, required, or needed. It should be appreciated that more than two retainers **31** may be implemented.

Figure 8 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** with a centrally located retainer **31**. The retainer **31** locates and retains the sample receptacle **21**, including the compartment **23** and seals **24**. The retainer **31** is shown holding or retaining the sample receptacle **21** from a substantially central location. It should be appreciated that the retainer **31** may be configured or arranged so as to hold the sample receptacle **21** vertically, horizontally, or at any angle as desired, required, or needed. It should be appreciated that the retainer **31** (or more than one retainer) may be located at any point along any side or portion of a sample receptacle **21** per sample receptacle **21**.

Figure 9 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** with a full length retainer **31**. The sample receptacle **21** is located within the cavity **33** of the retainer **31**. As shown, the retainer **31** has a cavity **33** configured to run parallel to the compartment **23** and seals **24**. The retainer **31** may be configured to enclose all or any portion of the length of the sample receptacle **21** as is desired or required by the user to allow for locating the sample receptacle **21** as necessary.

It should be appreciated that the sample receptacle **21** may be manufactured or formed of a material that is compatible with the particular type of beam scattering, diffraction, or spectroscopy that is used. Material choice should account for such factors as the chemical properties of the samples to be tested to ensure there is no degradation of the sample or the sample receptacle **21**, the temperatures and pressures that the testing (or analyzing, passing, accessing, or through-putting) will take place at, and the specific interaction of the material with the beam that will be used. In particular, it may be useful to select a material which is transparent or translucent to x-ray wavelengths of electromagnetic radiation. Other potential wavelengths that may be used in testing include gamma wavelengths, ultraviolet wavelengths, visible wavelengths, or infrared wavelengths. Beams composed of particles, such as electrons or neutrons, may also be used in conjunction with the present invention sample holding device, and their interaction with the particular material of choice should be considered. Said differently and by way of example, the material choice should allow for the particular beam that is to be used in testing to pass through the material of the sample receptacle **21** with as little interaction, hindrance, or absorption as possible to so as to allow the beam to interact principally with the sample entrained within. However, it should also be

appreciated that it may be useful to select a material that is transparent or translucent to one wavelength of electromagnetic radiation or one type of beam, but that is opaque to another. For example, some samples may be sensitive or degraded by visible wavelengths of light, but the user may wish to test them with an x-ray beam. In this particular, non-limiting example, a material which is opaque to visible light but transparent or translucent to x-ray wavelengths would be desirable for that particular application.

For the preceding discussion of **Figures 1-9**, it should be appreciated that any parts, such as adapters or inserts, any means for attachment or retention, material selections, sealing means, locations of components, or other features described in one figure may be applied equally to any other figure shown. **Figures 1-9** are given for exemplary purposes only, and are not limiting examples. Other configurations of retainer or sample receptacle may be used as desired or required to fit existing laboratory equipment (or yet to be designed laboratory equipment) and allow the usage of a sample receptacle that consists of a polymer, polymeric material, cellulose, cellulosic material, or any combination thereof. It should be appreciated that the related components or portions of the related components as discussed herein may take on all shapes along the entire continual geometric spectrum of manipulation of x, y and z planes to provide and meet the structural demands and operational requirements.

It should be appreciated that various sizes, dimensions, contours, rigidity, shapes, flexibility and materials of any of the components or portions of components in the various embodiments discussed throughout may be varied and utilized as desired or required.

Still referring to **Figures 1-9**, it should be appreciated that the sealing of the sample receptacle **21** may be achieved in any number of ways, both dependent upon the retainer **31** and independent of the retainer **31**. As shown, the sample receptacle **21** may be sealed itself. However, it should be appreciated that the sample receptacle **21** may be sealed in such a way as to depend upon the retainer **31**. For example, the sample receptacle may be sealed through the use of any one of the attachment or retention means mentioned above. The sample receptacle **21** may be bonded, glued, or melted into the retainer **31** to seal the compartment **23**. It is also possible that the adapter or insert **34** may be used in such a way as to seal the sample receptacle **21** when the adapter or insert **34** is used to retain or attach the sample receptacle **21** to the retainer **31**. Furthermore, the sample receptacle **21** may be used with or without a retainer **31**, and in any of the preceding examples, the retainer is configured to removably hold or locate the sample receptacle **31**. Said differently, the sample receptacle **21**

may be inserted and removed from the retainer **31** to allow for the use of multiple sample receptacles **21** with a single retainer **31**, or vice versa.

Figure 10 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device located in a rack, such as a linear rack **51**. The rack **51** may have multiple bays **52** which are configured to house one or more retainers **31** that house sample receptacles **21**. Alternatively, it should be appreciated that the rack **51** and its constituent bays **52** may be configured so as to directly house one or more sample receptacles **21** without the need for retainers **31**. The rack **51** may be configured to hold any number of retainers **31** or sample receptacles **21** as desired or required, from a minimum of one, up to any number as is practical for the equipment and space limitations of the laboratory where it is being used. Furthermore, it should be appreciated that the rack **51** may be composed of multiple linear sections, making it possible to arrange the bays **52** in a two dimensional array. This array may be in the form of a rectangle, square, polygon, closed curved shape, or any other shape that is practical for any particular application or testing apparatus.

Figure 11 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device located in a rack, such as a circular or round rack **51**. The rack **51** may have one or multiple bays **52**, which are configured to house retainers **31** that house sample receptacles **21**. Alternatively, it should be appreciated that the rack **51** and its constituent bays **52** may be configured so as to directly house one or more sample receptacles **21** without the need for retainers **31**. The rack **51** may be configured to hold any number of retainers **31** or sample receptacles **21** as desired or required, from a minimum of one, up to any number as is practical for the equipment and space limitations of the laboratory where it is being used. Furthermore, it should be appreciated that the rack **51** may be composed of multiple circular or rounded sections, concentric or otherwise, making it possible to arrange the bays **52** in a two dimensional array. The rack **51** may take on any number of geometries, including open or closed curved or curvilinear shapes. These curvilinear shapes may include, though not limited to, circular, semi-circular, oval, elliptical, parabolic, hyperbolic, or semi oval shapes.

It should be appreciated that the rack **51** may take on any number of geometries, including any three-dimensional shape, such as but not limited thereto, spherical, cubical, cuboid, prismatic, pyramidal, tubular, or cylindrical.

Figure 12 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device located in a rack, such as a flexible or articulating

rack **51**. The rack **51** may be composed of one or more bays **52**, which are configured to house retainers **31** that house sample receptacles **21**. Alternatively, it should be appreciated that the rack **51** and its constituent bays **52** may be configured so as to directly house one or more sample receptacles **21** without the need for retainers **31**. Disposed between the bays **52** are multiple flexible or hinged members **54**. These flexible or hinged members **54** allow the bays **52** to articulate or move relative to one another. This allows the rack **51** to function as a chain or magazine of sample receptacles **21** to allow for rapid testing (or analyzing, passing, accessing, or through-putting) of multiple samples while allowing for continuous removal and replacement of sample receptacles **21**, and optionally their retainers **31**. Said differently, the flexible or articulating rack **51** allows for one sample receptacle **21** to be located in the test chamber, tested, and then a movement or rotation of the rack **51**, as if it were a chain or belt, to move another sample receptacle **21** into place for further testing (or analyzing, passing, accessing, or through-putting). While this motion takes place, other bays **52** may be located outside of the testing area, allowing sample receptacles **21** or retainers **31** to be removed and replaced in the rack **51**, allowing for continuous testing (or analyzing, passing, accessing, or through-putting) of a number of samples greater than the number of bays **52** in the rack **51**. It should be appreciated that the rack **51** may have any number of bays as desired or required, including the ability to add or subtract bays as modular elements. Furthermore, the flexible or hinged members **54** may be composed of flexible materials, such as wires, rubber components, elastomeric components, or any other material that easily deflects, or they may be made of hinged rigid components as with a chain.

The preceding discussion of **Figures 10-12** serves to illustrate the fact that the sample receptacles **21** and their optional retainers **31** may be particularly well suited to testing (or analyzing, passing, accessing, or through-putting) large numbers of samples in a relatively short period of time. The preceding discussion of **Figures 10-12** serves to illustrate the fact that the sample receptacles **21** and their optional retainers **31** may be particularly well suited to testing (or analyzing, passing, accessing or through-putting) large numbers of samples in a relatively automated and efficient manner. Because the sample receptacles **21** are composed of a polymer, polymeric material, cellulose, cellulosic material, or any combination thereof, the sample receptacles **21** are inexpensive, easy to manufacture in great numbers, and easy to load and seal quickly and reliably allowing for testing (or analyzing, passing, accessing, or through-putting) many more samples than would be possible with glass or quartz based components. Furthermore, it should be appreciated that the recovery of the sample from the

sample receptacle **21** would be comparatively simple because the nature of the polymer, polymeric material, cellulose, or cellulosic material is such that the sample could easily be recovered either through use of a syringe or other removal or extraction tool or device, or through cutting or tearing the sample receptacle **21** to allow removal of the sample without contamination or degradation. This advantage allows for samples that are very difficult to prepare in large quantities to be tested through beam scattering and diffraction methods without the drawback of potential sample loss due to the use of glass or quartz components. Furthermore, it should be appreciated that the inexpensive and easy to use nature of the present invention sample holding device allows for the sample receptacle **21** to be a disposable device, reducing the need for constant cleaning and repair of laboratory equipment. It should also be appreciated that the retainer **31** and any other parts of the invention may be made from inexpensive materials that are conducive to mass production allowing for virtually any part of the device or invention to be made in large quantities. Consequently, the device and its associated parts may be disposable and offer further advantages over a glass or quartz component.

Figure 13 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device sample receptacles **21**. As shown, the sample receptacle **21** may take any number of shapes or sizes as desired or required. In particular, a larger sample receptacle **21** may be used for samples (not shown) which are larger or easy to procure, while smaller sample receptacles **21** may be used for samples (not shown) which are harder to procure or produce. Regardless of the shape or size, the sample receptacle **21** will be comprised of a compartment **23** and one or more seals **24**. Optionally, the sample receptacle **21** may include one or more access apertures **22** which allows for insertion and removal of the sample from the compartment or compartments **23**. This access aperture **22** may be a one way valve, a diaphragm which may be pierced by a syringe and self seal upon retraction of the syringe, a fitting, or any other device which would allow for insertion and removal of the sample. It should be appreciated that the access aperture **22** may be configured to be integral with the sample receptacle **21** or it may be manufactured as a separate part that is attached to the sample receptacle **21** with an adhesive, press joint, threaded joint, interference fit, or any other means or method of attachment, securing, or anchoring as desired or required.

Figure 14 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device retainer **31**. This retainer **31** is shown for illustrative

purposes and is only one of many possible configurations for a retainer **31** that may be used to replace existing retainers or sample holders in existing laboratory equipment (as well as other or future designed laboratory equipment). The retainer **31** includes a cavity **33** that is configured to accept a sample receptacle (not shown). Within the cavity **33** is a wavelength access aperture **32** which allows the scattering or diffraction beam to pass through the retainer **31** and intersect with the sample receptacle (not shown). It should be appreciated that the sample receptacle would be aligned with the wavelength access aperture **32** to allow the scattering or diffraction beam to pass through the sample receptacle and the sample. This specific, non-limiting, example of a retainer **31** is fitted with an alignment pin **35** and an alignment cap **37** to allow the retainer **31** to work with a specific piece of laboratory equipment used in beam scattering or diffraction techniques. The retainer **31** also includes a retrieval pin **36** to allow for easy removal of the retainer **31** from a laboratory apparatus. It should be appreciated that the retainer **31** may take on any configuration or geometry as desired or required to allow for the retainer **31** to be used with any make or model of equipment that may already be present in the user's laboratory (or to be compatible with future designs).

Although not shown, it should be appreciated that more than one cavity **33** may be provided within a given retainer **31**. It should be appreciated that more than one wavelength access aperture **32** may be provided within a given cavity **33** (or other portion of a retainer device **31** if applicable). It should be appreciated that the access aperture **32** may be any size or shape as desired or required. It should be appreciated that if the retainer **31** does not include a cavity **33** then a wavelength access aperture **32** may be provided on a portion or location of the retainer device **31** to which would allow the scattering or diffraction beam to pass through the retainer **31** and intersect with the sample receptacle (not shown). Moreover, if there are multiple wavelength access apertures **32** then one or more wavelength apertures may be located in the cavity **33** of the retainer device **31** and one or more wavelength apertures may be located on a non-cavity portion of the retainer device **31**.

Figure 15 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11**. A retainer **31** is in communication with a sample receptacle **21**, which is located in a cavity **33** configured to receive the sample receptacle **21**. The cavity **33** is configured to align the compartment **23** of the sample receptacle **21** with the wavelength access aperture **32** to allow a scattering or diffraction beam to pass through the compartment **23** and the sample. The wavelength access aperture **32** is

indicated with dashed lines to delineate a location on the back side of the retainer **31** for this particular view of the illustration. Seals **24** at either end of the compartment **23** ensure that the sample (not shown) remains entrained in the sample receptacle **21** even if the device **11** is placed in a vacuum or other environment that could potentially degrade or contaminate the sample. Seals **24** at either end of the compartment **23** ensure that the sample (not shown) remains entrained even if the device **11**, retainer **31**, or sample receptacle **21** is moved, jarred or transported. The retainer **31** in this specific, non-limiting, example is configured to have an alignment pin **35** and alignment cap **37** to allow the retainer **31** to interact with other laboratory equipment that is used during beam scattering and diffraction testing. The retainer **31** also features a retrieval pin **36** to allow easy removal of the retainer **31** from the beam scattering and diffraction test equipment.

Figure 16 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device **11** and some exemplary constituent parts. A sample receptacle **21** with a compartment **23**, seals **24**, and an access aperture **22** may be configured to be received by two adapters or inserts **34**. The adapters or inserts **34** are configured with adapter apertures **38**, and at least one of the adapters or inserts **34** may be configured to have a depression or crease **39** configured to receive the sample receptacle **21**. A retainer **31**, featuring an alignment pin **35**, alignment cap **37**, and a retrieval pin **36**, has a cavity **33** that may be configured to accept the sample receptacle **21** which is sandwiched between the two adapters or inserts **34**. When assembled, the adapter apertures **38** of the adapters or inserts **34** are aligned with the wavelength access aperture (not shown) of the retainer **31** to allow a scattering beam to pass unhindered through the sample receptacle **21**. It should be appreciated that more than one adapter aperture **38** may be provided within a given adapter or insert **34**. It should be appreciated that the adapter aperture **38** may be any size or shape as desired or required. It should be appreciated that one or more adapters or inserts **34** may be utilized for a given retainer **31**.

Figure 17 provides a schematic illustration of an aspect of an embodiment of the present invention sample holding device in an exemplary moveable rack **51**. A linear rack **51** with multiple bays **52** is shown with a retainer **31** housed in one of the bays **52**. The removal pin **36** of the retainer **31** is visible protruding out from the bay **52**. The rack **51** is in communication with a track or feed mechanism **53** to allow for translation of the rack **51** so that multiple samples in the several bays **52** may be tested in sequence. It should be appreciated that the track or feed mechanism **53** may take any number of forms or

configurations including, but not limited to, feed screws, tracks, racks, chains, belts, or helical screws.

It should be appreciated that any of the components or portions of the related components as discussed herein may take on all shapes along the entire continual geometric spectrum of manipulation of x, y and z planes to provide and meet the structural demands and operational requirements.

It should be appreciated that various sizes, dimensions, contours, rigidity, shapes, flexibility and materials of any of the components or portions of components in the various embodiments discussed throughout may be varied and utilized as desired or required.

An aspect of various embodiments of the present invention sample holding device (and related systems and methods) may provide a number of advantages. For instance, the related materials of the sample receptacle are robust and resist fracture and breakage. The sample receptacle is easy to access, as well as to load and remove specimens or other materials therefrom. Similarly, the retainer is easy to access, as well as to load and remove sample receptacles therefrom. Still yet, the retainer and/or sample receptacle are easy to load and remove from the rack or other device, system or mechanism. Moreover, the sample receptacle and related components and/or the retainer and related components may provide a vacuum tight seal. Furthermore, it should be appreciated that the sample receptacle and related components and/or the retainer and related components can be easy to use with numerous different types of systems which may incorporate x-rays, gamma rays, ultraviolet light, visible light, infrared light, or any other wavelength or frequency of the electromagnetic spectrum that may be desired or required by the user. The various components of the sample holding device may be readily transported either individually or collectively (or both), or practiced in a permanent facility or mobile facility (or both).

EXAMPLES

Practice of an aspect of an embodiment (or embodiments) of the invention will be still more fully understood from the following examples, which are presented herein for illustration only and should not be construed as limiting the invention in any way.

Example 1. A device for use in solution scattering or diffraction, the device comprising: at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at

least one sample receptacle configured to accommodate a sample; a retainer, the retainer configured to removably hold the at least one sample receptacle and allow for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and wherein the at least one sample receptacle is configured to be sealable for containing the sample, wherein sealing is independent of the retainer.

Example 2. The device of example 1, wherein the scattering beam or diffraction beam is an x-ray beam.

Example 3. The device of example 1 (as well as subject matter of example 2), wherein each of the at least one sample receptacles comprises one or more access apertures.

Example 4. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-3), wherein each of the at least one sample receptacles comprises one or more compartments.

Example 5. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-4), wherein the sealing of at least one the sample receptacle comprises one or more of any combination of the following: heat seal, mechanical seal, adhesion seal, or chemical seal.

Example 6. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-5), wherein the at least one sample receptacle is compatible with gamma wavelengths, x-ray wavelengths, ultraviolet wavelengths, visible wavelengths, or infrared wavelengths.

Example 7. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-6), wherein the at least one sample receptacle is opaque to visible wavelengths.

Example 8. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-7), wherein the at least one sample receptacle is translucent or transparent to x-ray wavelengths.

Example 9. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-8), wherein the at least one sample receptacle comprising a plurality of compartments.

Example 10. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-9), wherein the sample receptacle is configured to allow for recovery of the sample from the sample receptacle.

Example 11. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-10), wherein the at least one sample receptacle is disposable.

Example 12. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-11), wherein the retainer configured to hold at least one of the sample receptacles by one or more of any combination of the retention modes: friction fit retention, interference fit retention, magnetic retention, mechanical retention, or adhesive retention.

Example 13. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-12), wherein the retainer is disposable.

Example 14. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-13), further comprising a rack to hold the retainer.

Example 15. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-14), wherein the rack is configured to hold a plurality of the retainers.

Example 16. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-15), wherein the rack is configured to align the plurality of retainers linearly.

Example 17. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-15), wherein the rack is configured to align the plurality of retainers curvilinearly.

Example 18. The device of example 16 (as well as subject matter of one or more of any combination of examples 2-17), wherein the curvilinear alignment includes circular, semi-circular, oval, elliptical, parabolic, hyperbolic, or semi-oval.

Example 19. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-18), wherein the rack is configured to allow pivoting of one or more of the retainers with respect to one or more of other the retainers.

Example 20. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-19), further comprising: a scattering system or diffraction system, or both a scattering and diffraction system. The scattering or diffraction system comprising: a source configured to pass a scattering beam or diffraction beam through the at least one sample receptacle; and a detector configured to receive a scattered beam or diffracted beam exiting from the at least one sample receptacle.

Example 21. The device of example 20 (as well as subject matter of one or more of any combination of examples 2-19), wherein the scattering system or diffraction system is an x-ray system.

Example 22. The device of example 20 (as well as subject matter of one or more of any combination of examples 2-19 and 21), wherein the scattering system or diffraction system is a gamma system, ultraviolet system, visible system, or infrared system.

Example 23. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-19 and 21-22), wherein the at least one sample receptacle is configured in at least one or more of the following shapes: spherical, cubical, cuboid, prismatic, pyramidal, tubular, or cylindrical.

Example 24. A method for solution scattering or diffraction, the method comprising: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle accommodating a sample; holding the at least one sample receptacle and allowing for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and sealing the at least one sample receptacle for containing the sample.

Example 25. The method of example 24, wherein the scattering beam or diffraction beam comprises x-ray wavelengths.

Example 26. The method of example 24 (as well as subject matter of example 25), wherein the scattering beam or diffraction beam comprises gamma, ultraviolet, visible, or infrared wavelengths.

Example 27. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-26), wherein the holding is provided by a retainer, wherein the retainer is configured to removably hold the at least one sample receptacle.

Example 28. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-27), wherein the sealing of the at least one sample receptacle is independent of the retainer.

Example 29. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-28), wherein the sealing of the at least one sample receptacle is dependent upon the retainer.

Example 30. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-29), wherein the accommodation is provided by inserting

the sample into the at least one sample receptacle through one or more access apertures of the at least one sample receptacle.

Example 31. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-30), wherein the sealing of at least one the sample receptacles comprises one or more of any combination of the following: heat seal, mechanical seal, adhesion seal, or chemical seal.

Example 32. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-31), wherein the at least one sample receptacle is compatible with gamma wavelengths, x-ray wavelengths, ultraviolet wavelengths, visible wavelengths, or infrared wavelengths.

Example 33. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-32), further comprising: recovering the sample from the sample receptacle.

Example 34. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-33), further comprising loading one or more of the retainers into a rack.

Example 35. The method of example 24 (as well as subject matter of one or more of any combination of examples 25-34), further comprising: passing a scattering beam or diffraction beam through the at least one sample receptacle; and receiving and detecting a scattered beam or diffracted beam exiting from the at least one sample receptacle.

Example 36. A method for solution scattering or diffraction, the method comprising: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle configured to accommodate a sample; providing a retainer configured for holding the at least one sample receptacle and allowing for the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and the sample receptacle configured to allow the sample to be sealed in the at least one sample receptacle for containing the sample.

Example 37. The method of example 36, wherein the scattering beam or diffraction beam comprises x-ray wavelengths.

Example 38. The method of example 36 (as well as subject matter of example 37), wherein the scattering beam or diffraction beam comprises gamma, ultraviolet, visible, or infrared wavelengths.

Example 39. The method of example 36 (as well as subject matter of one or more of any combination of examples 37-38), wherein the holding is provided to removably hold the at least one sample receptacle.

Example 40. The method of example 36 (as well as subject matter of one or more of any combination of examples 37-39), wherein the sealing of the at least one sample receptacle is independent of the retainer.

Example 41. The method of example 36 (as well as subject matter of one or more of any combination of examples 37-40), wherein the sealing of the at least one sample receptacle is dependent upon the retainer.

Example 42. A method for solution scattering or diffraction, the method comprising: providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, the at least one sample receptacle configured to accommodate a sample; wherein the at least one sample receptacle is configured to allow the at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and the sample receptacle configured to allow the sample to be sealed in the at least one sample receptacle for containing the sample.

Example 43. The device of example 1 (as well as subject matter of one or more of any combination of examples 2-23), wherein said scattering beam or diffraction beam is one or more of the following: gamma beam, ultraviolet beam, visible beam, or infrared beam.

Example 44. The device of example 43 (as well as subject matter of one or more of any combination of examples 2-23), wherein said scattering beam or diffraction beam further comprises an x-ray beam.

Example 45. The method of examples 24-35, 36-41, or 42, further comprising using any of the components (of the devices or systems) provided in any one or more of examples 1-23 and 43-44.

Example 46. The method of manufacturing any of the components (of the devices or systems) provided in any one or more of examples 1-23 and 43-44.

REFERENCES

The devices, systems, compositions, components, and methods of various embodiments of the invention disclosed herein may utilize aspects disclosed in the following

references, applications, publications and patents and which are hereby incorporated by reference herein in their entirety (and which are not admitted to be prior art with respect to the present invention by inclusion in this section):

1. U.S. Patent Application Publication No. US 2013/0101091 A1, Garvey, et al., “Sealed Detector Array for the Collection of Both Wide Angle and Small Angle X-ray Scattering”, April 28, 2013.
2. International Patent Application No. WO 2013/025737 A1, Garvey, et al., “Sealed Detector Array for the Collection of Both Wide Angle and Small Angle X-ray Scattering.
3. U.S. Patent Application Serial No. US 2011/0135990 A1, Yamamoto, et al., “Sodium Secondary Battery”, June 9, 2011.
4. Lipfert, J., et al., “Sample holder for small-angle x-ray scattering static and flow cell measurements”, Rev. Sci. Instrum. 77,046108, (2006), pp. 1-3.
5. Toft, K., et al., “High-Throughput Small Angle X-ray Scattering from Proteins in Solution Using a Microfluidic Front-End”, Analytical Chemistry, Vol. 80, No. 10, May 15, 2008, pp. 3648-3654.
6. Soliman, A., et al., “Development of high-performance X-ray transparent crystallization plates for *in situ* protein crystal screening and analysis”, Acta Crys. (2011), D67, pp. 646-656.
7. Kalinin, Y., et al., “Crystal growth in X-ray-transparent plastic tubing: an alternative for high-throughput applications”, Acta Cryst. (2005), D61, pp. 1528-1532.

In summary, while the present invention has been described with respect to specific embodiments, many modifications, variations, alterations, substitutions, and equivalents will be apparent to those skilled in the art. The present invention is not to be limited in scope by the specific embodiment described herein. Indeed, various modifications of the present invention, in addition to those described herein, will be apparent to those of skill in the art from the foregoing description and accompanying drawings. Accordingly, the invention is to be considered as limited only by the spirit and scope of the following claims, including all modifications and equivalents.

Still other embodiments will become readily apparent to those skilled in this art from reading the above-recited detailed description and drawings of certain exemplary embodiments. It should be understood that numerous variations, modifications, and

additional embodiments are possible, and accordingly, all such variations, modifications, and embodiments are to be regarded as being within the spirit and scope of this application. For example, regardless of the content of any portion (e.g., title, field, background, summary, abstract, drawing figure, etc.) of this application, unless clearly specified to the contrary, there is no requirement for the inclusion in any claim herein or of any application claiming priority hereto of any particular described or illustrated activity or element, any particular sequence of such activities, or any particular interrelationship of such elements. Moreover, any activity can be repeated, any activity can be performed by multiple entities, and/or any element can be duplicated. Further, any activity or element can be excluded, the sequence of activities can vary, and/or the interrelationship of elements can vary. Unless clearly specified to the contrary, there is no requirement for any particular described or illustrated activity or element, any particular sequence or such activities, any particular size, speed, material, dimension or frequency, or any particularly interrelationship of such elements. Accordingly, the descriptions and drawings are to be regarded as illustrative in nature, and not as restrictive. Moreover, when any number or range is described herein, unless clearly stated otherwise, that number or range is approximate. When any range is described herein, unless clearly stated otherwise, that range includes all values therein and all sub ranges therein. Any information in any material (e.g., a United States/foreign patent, United States/foreign patent application, book, article, etc.) that has been incorporated by reference herein, is only incorporated by reference to the extent that no conflict exists between such information and the other statements and drawings set forth herein. In the event of such conflict, including a conflict that would render invalid any claim herein or seeking priority hereto, then any such conflicting information in such incorporated by reference material is specifically not incorporated by reference herein.

CLAIMS:

We claim:

1. A device for use in solution scattering or diffraction, said device comprising:
at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, said at least one sample receptacle configured to accommodate a sample;
a retainer, said retainer configured to removably hold said at least one sample receptacle and allow for said at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and
wherein said at least one sample receptacle is configured to be sealable for containing the sample, wherein sealing is independent of said retainer.
2. The device of claim 1, wherein said scattering beam or diffraction beam is an x-ray beam.
3. The device of claim 1, wherein each of said at least one sample receptacles comprises one or more access apertures.
4. The device of claim 1, wherein each of said at least one sample receptacles comprises one or more compartments.
5. The device of claim 1, wherein said sealing of at least one said sample receptacle comprises one or more of any combination of the following: heat seal, mechanical seal, adhesion seal, or chemical seal.
6. The device of claim 1, wherein said at least one sample receptacle is compatible with gamma wavelengths, x-ray wavelengths, ultraviolet wavelengths, visible wavelengths, or infrared wavelengths.
7. The device of claim 1, wherein said at least one sample receptacle is opaque to visible wavelengths.

8. The device of claim 1, wherein said at least one sample receptacle is translucent or transparent to x-ray wavelengths.
9. The device of claim 1, wherein said at least one sample receptacle comprising a plurality of compartments.
10. The device of claim 1, wherein said sample receptacle is configured to allow for recovery of the sample from said sample receptacle.
11. The device of claim 1, wherein said at least one sample receptacle is disposable.
12. The device of claim 1, wherein said retainer configured to hold at least one of said sample receptacles by one or more of any combination of the retention modes: friction fit retention, interference fit retention, magnetic retention, mechanical retention, or adhesive retention.
13. The device of claim 1, wherein said retainer is disposable.
14. The device of claim 1, further comprising a rack to hold said retainer.
15. The device of claim 1, wherein said rack is configured to hold a plurality of said retainers.
16. The device of claim 1, wherein said rack is configured to align said plurality of retainers linearly.
17. The device of claim 1, wherein said rack is configured to align said plurality of retainers curvilinearly.
18. The device of claim 16, wherein said curvilinear alignment includes circular, semi-circular, oval, elliptical, parabolic, hyperbolic, or semi-oval.

19. The device of claim 1, wherein said rack is configured to allow pivoting of one or more of said retainers with respect to one or more of other said retainers.

20. The device of claim 1, further comprising:
a scattering system or diffraction system, or both a scattering and diffraction system, said scattering or diffraction system comprising:
a source configured to pass a scattering beam or diffraction beam through said at least one sample receptacle; and
a detector configured to receive a scattered beam or diffracted beam exiting from said at least one sample receptacle.

21. The device of claim 20, wherein said scattering system or diffraction system is an x-ray system.

22. The device of claim 20, wherein said scattering system or diffraction system is a gamma system, ultraviolet system, visible system, or infrared system.

23. The device of claim 1, wherein said at least one sample receptacle is configured in at least one or more of the following shapes: spherical, cubical, cuboid, prismatic, pyramidal, tubular, or cylindrical.

24. A method for solution scattering or diffraction, said method comprising:
providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, said at least one sample receptacle accommodating a sample;
holding said at least one sample receptacle and allowing for said at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and
sealing said at least one sample receptacle for containing the sample.

25. The method of claim 24, wherein said scattering beam or diffraction beam comprises x-ray wavelengths.

26. The method of claim 24, wherein said scattering beam or diffraction beam comprises gamma, ultraviolet, visible, or infrared wavelengths.
27. The method of claim 24, wherein said holding is provided by a retainer, wherein said retainer is configured to removably hold said at least one sample receptacle.
28. The method of claim 24, wherein said sealing of said at least one sample receptacle is independent of said retainer.
29. The method of claim 24, wherein said sealing of said at least one sample receptacle is dependent upon said retainer.
30. The method of claim 24, wherein said accommodation is provided by inserting the sample into said at least one sample receptacle through one or more access apertures of said at least one sample receptacle.
31. The method of claim 24, wherein said sealing of at least one said sample receptacles comprises one or more of any combination of the following: heat seal, mechanical seal, adhesion seal, or chemical seal.
32. The method of claim 24, wherein said at least one sample receptacle is compatible with gamma wavelengths, x-ray wavelengths, ultraviolet wavelengths, visible wavelengths, or infrared wavelengths.
33. The method of claim 24, further comprising:
recovering the sample from said sample receptacle.
34. The method of claim 24, further comprising loading one or more of said retainers into a rack.
35. The method of claim 24, further comprising:
passing a scattering beam or diffraction beam through said at least one sample receptacle; and

receiving and detecting a scattered beam or diffracted beam exiting from said at least one sample receptacle.

36. A method for solution scattering or diffraction, said method comprising:
providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, said at least one sample receptacle configured to accommodate a sample;
providing a retainer configured for holding said at least one sample receptacle and allowing for said at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and
said sample receptacle configured to allow the sample to be sealed in said at least one sample receptacle for containing the sample.

37. The method of claim 36, wherein said scattering beam or diffraction beam comprises x-ray wavelengths.

38. The method of claim 36, wherein said scattering beam or diffraction beam comprises gamma, ultraviolet, visible, or infrared wavelengths.

39. The method of claim 36, wherein said holding is provided to removably hold said at least one sample receptacle.

40. The method of claim 36, wherein said sealing of said at least one sample receptacle is independent of said retainer.

41. The method of claim 36, wherein said sealing of said at least one sample receptacle is dependent upon said retainer.

42. A method for solution scattering or diffraction, said method comprising:
providing at least one sample receptacle comprising, at least in part, a polymer material, polymeric material, cellulose material, cellulosic material, or any combination thereof, said at least one sample receptacle configured to accommodate a sample;

wherein said at least one sample receptacle is configured to allow said at least one sample receptacle to be in communication with a scattering beam or diffraction beam; and said sample receptacle configured to allow the sample to be sealed in said at least one sample receptacle for containing the sample.

43. The device of claim 1, wherein said scattering beam or diffraction beam is one or more of the following: gamma beam, ultraviolet beam, visible beam, or infrared beam.

44. The device of claim 43, wherein said scattering beam or diffraction beam further comprises an x-ray beam.

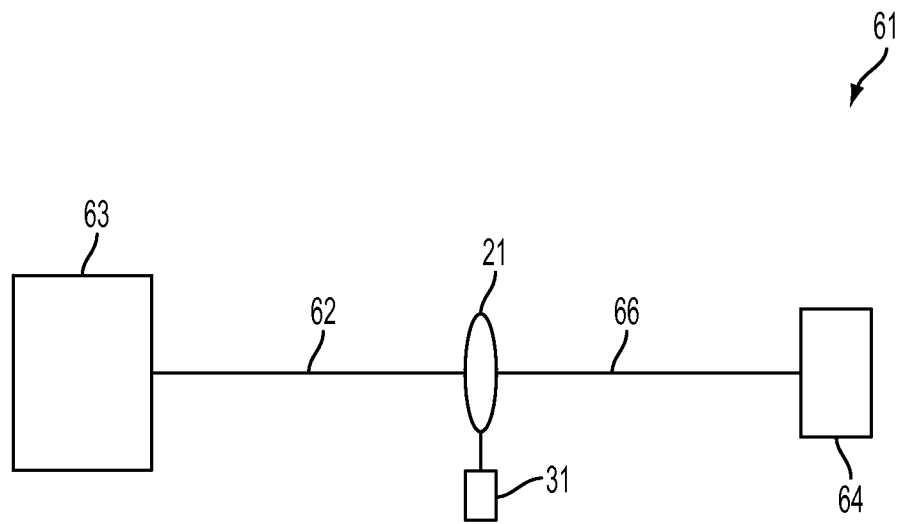


FIG. 1

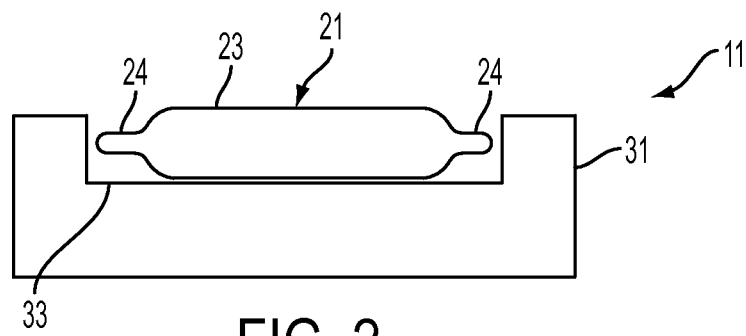


FIG. 2

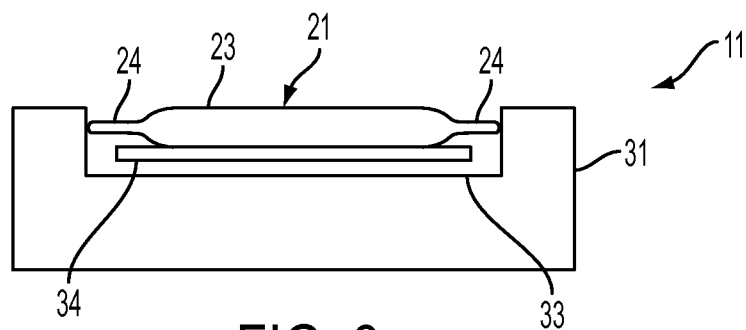


FIG. 3

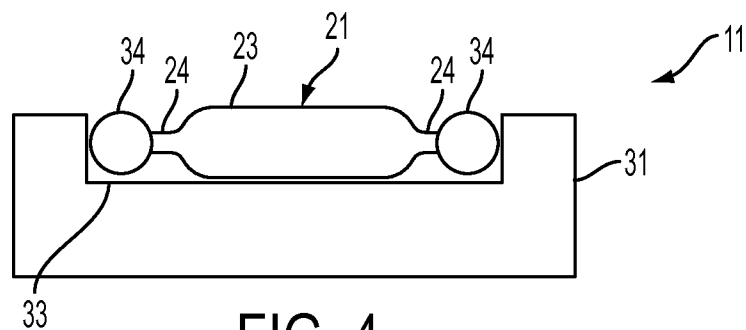


FIG. 4

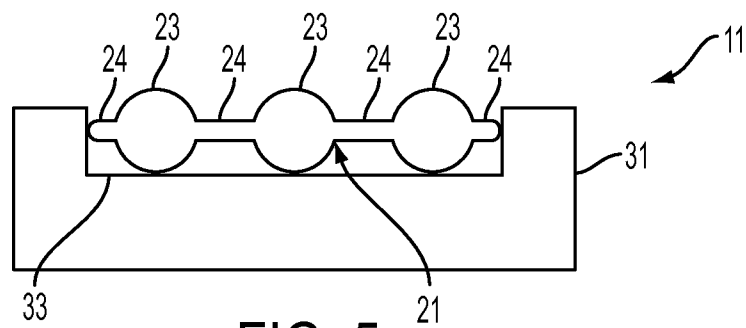


FIG. 5

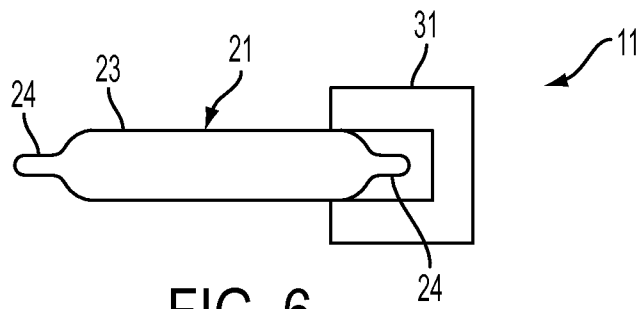


FIG. 6

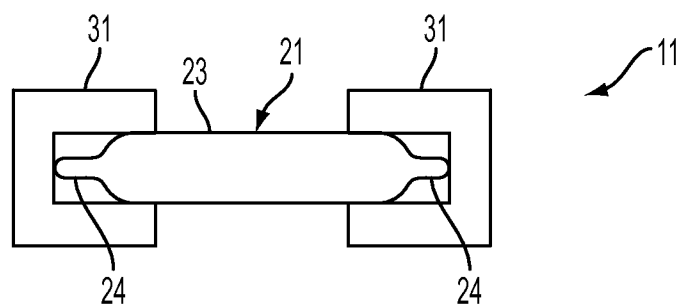


FIG. 7

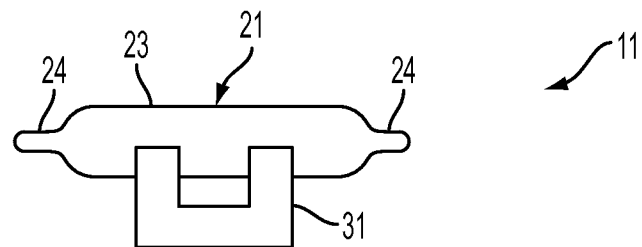


FIG. 8

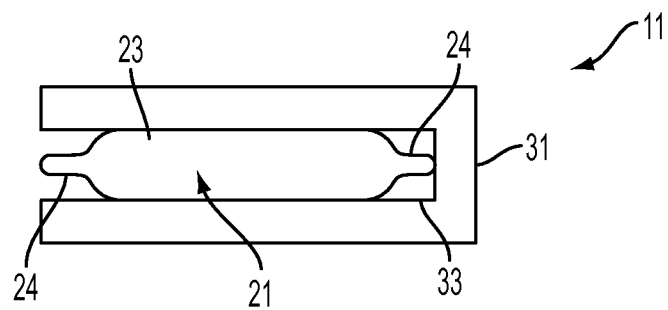


FIG. 9

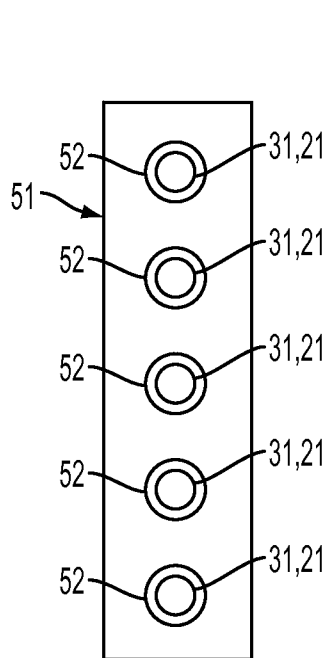


FIG. 10

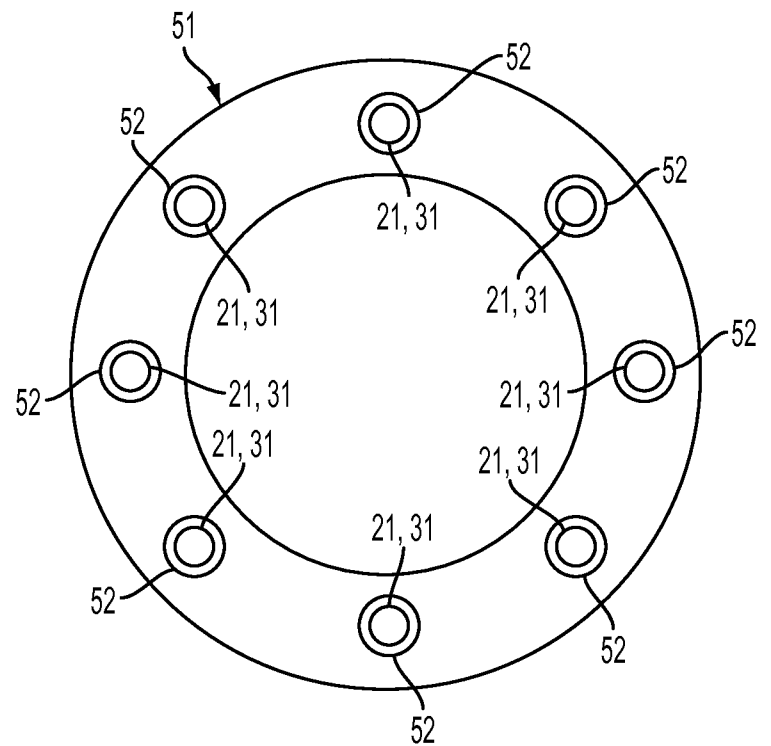


FIG. 11

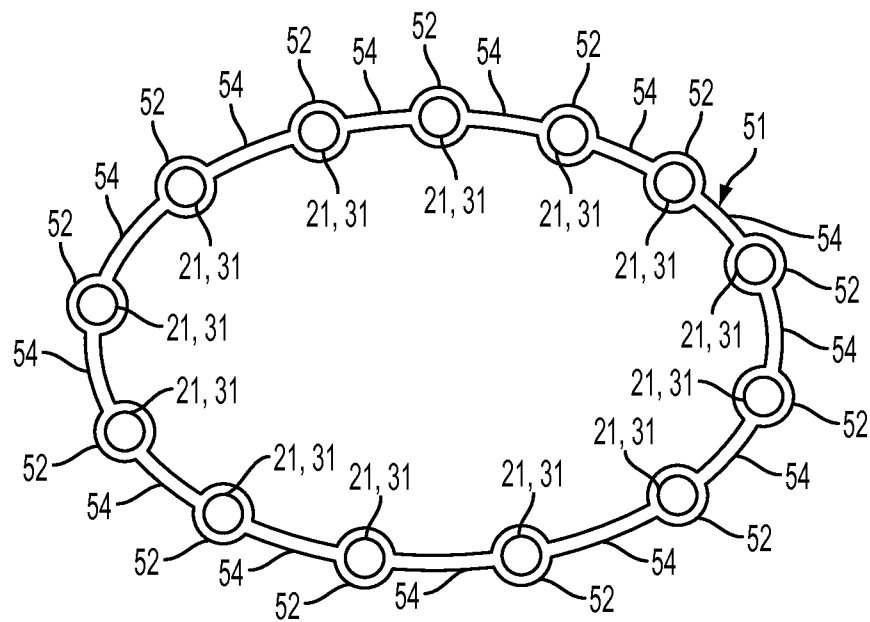


FIG. 12

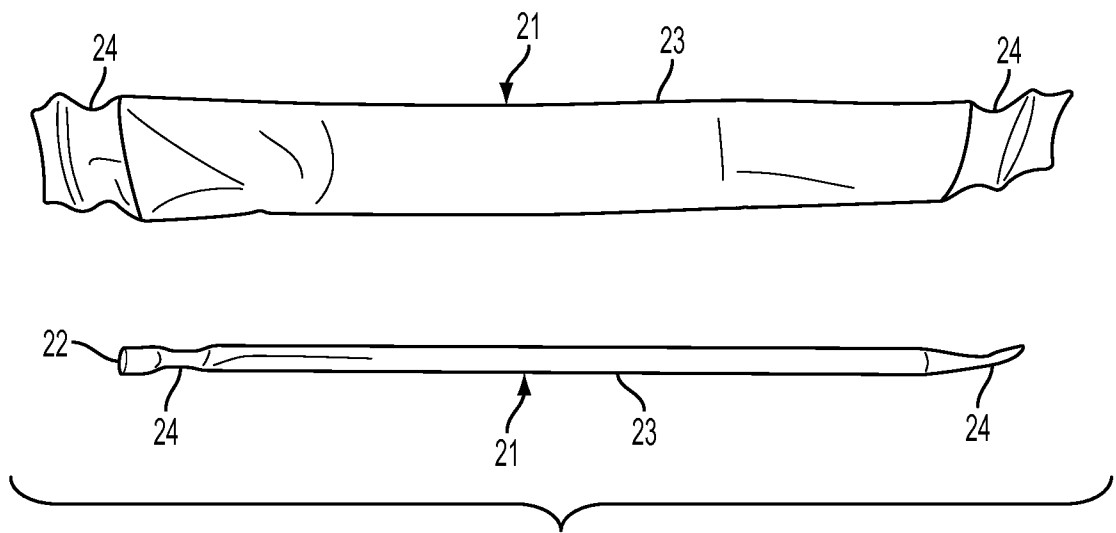


FIG. 13

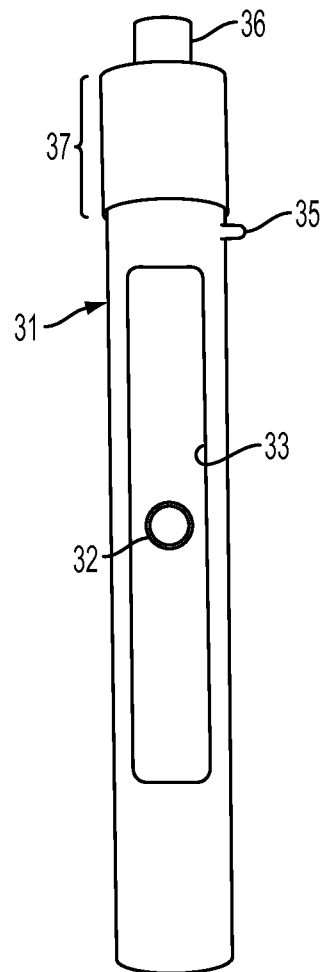


FIG. 14

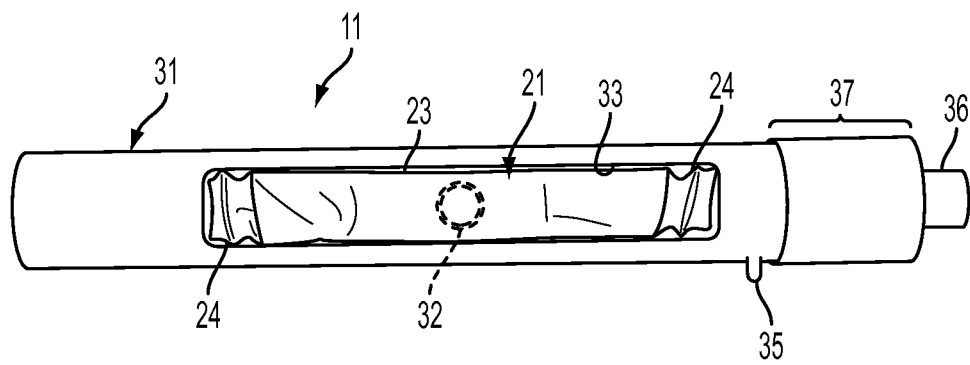
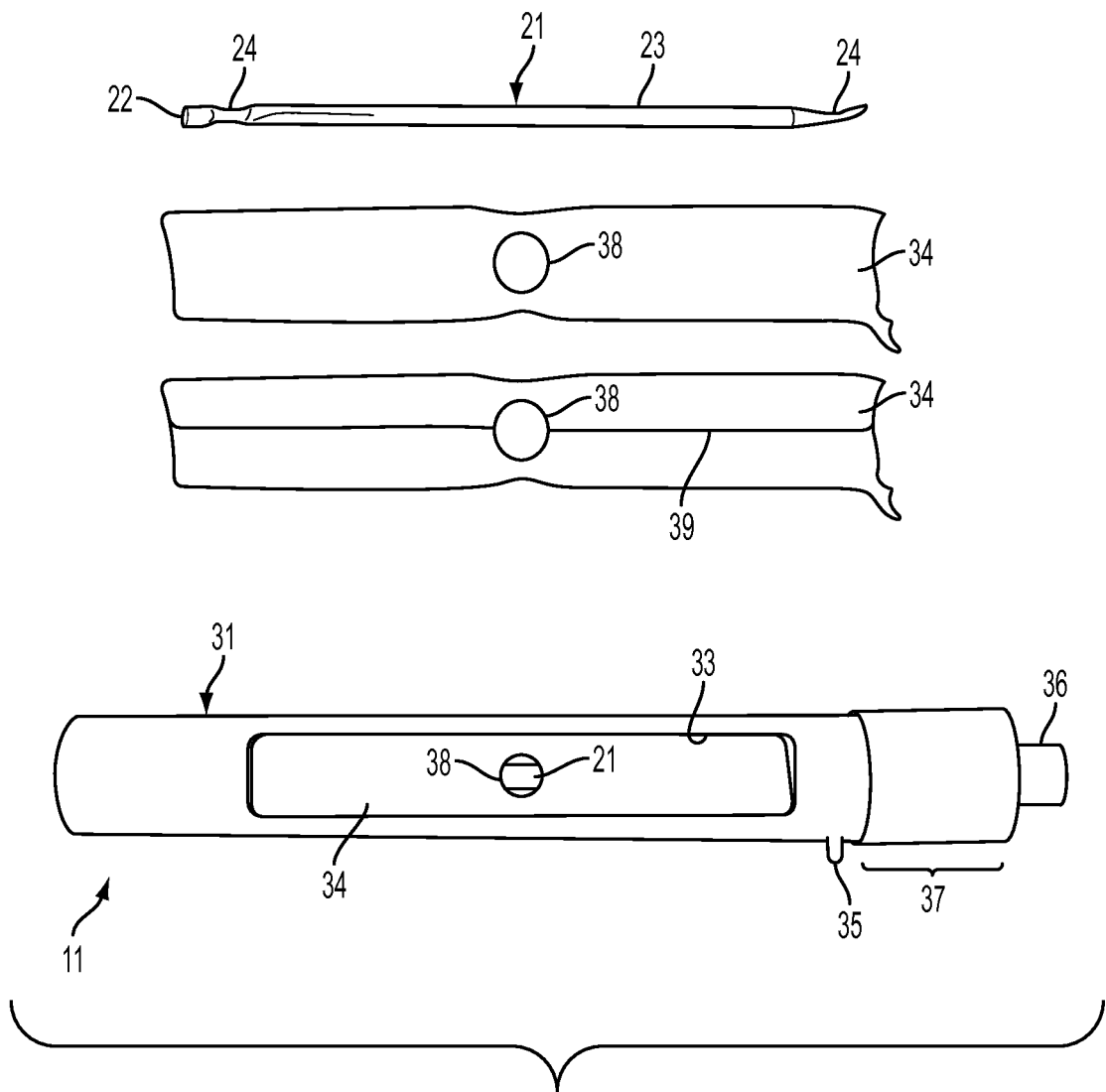


FIG. 15



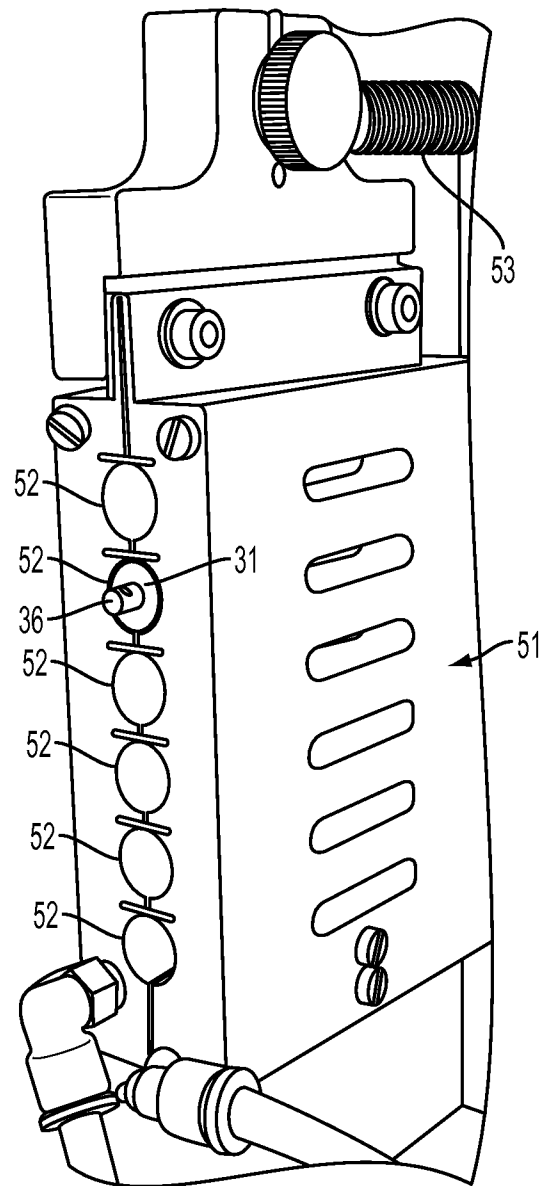


FIG. 17

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US2014/061263

A. CLASSIFICATION OF SUBJECT MATTER

IPC(8) - G01N 21.01 (2014.01)

CPC - G01N 21/01 (2014.11)

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC(8) - G01N 21/01, G01N-021/03, G01N-021/13 (2014.01)

USPC - 73/61.59, 211/1.52, 211/85.13, 211/165, 220/495.01, 220/495.05, 220/495.06

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

CPC - G01N 21/01, G01N-021/03, G01N-021/13, G01N-021/35, G01N-2021/0364, G01N-2021/0389 (2014.11) (keyword delimited)

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

Orbit, Google Patents, Google.

Search terms used: diffraction, scatter, specimen holder, sample holder, disposable, specimen container, sample holder rack

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2012/0322052 A1 (HALVERSON et al) 20 December 2012 (20.12.2012) entire document	1-8, 10-13, 20-33, 35-44
Y		9, 14-19, 34
Y	US 3,218,459 A (BENS) 16 November 1965 (16.11.1965) entire document	9
Y	US 3,859,528 A (LUITWIELER JR et al) 07 January 1975 (07.01.1975) entire document	14-19, 34

☐ Further documents are listed in the continuation of Box C.

* Special categories of cited documents:

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier application or patent but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

Date of the actual completion of the international search

28 December 2014

Date of mailing of the international search report

04 FEB 2015

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